



LT-171

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

PATENT APPLICATION

Applicant : Florin A. Oprescu
Application No.: 10/779,292 Confirm. No.: 7415
Filed : February 12, 2004
For : BUFFERED OVERSAMPLING ANALOG-TO-DIGITAL
CONVERTER WITH IMPROVED DC OFFSET
PERFORMANCE
Group Art Unit : 2819
Examiner : Brian K. Young

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56 and 1.97, applicant hereby makes the following documents of record in the above-identified patent application:

U.S. Patent Documents

4,684,925	Maruta	08/04/87
4,704,600	Uchimura et al.	11/03/87
4,876,542	Van Bavel et al.	10/24/89
4,876,544	Kuraishi	10/24/89
5,010,347	Yukawa	04/23/91
5,148,167	Ribner	09/15/92
5,396,245	Rempfer	03/07/95
5,450,083	Brewer	09/12/95
5,675,334	McCartney	10/07/97

Express Mail No.
EV 132191896 US

5,870,048	Kuo et al.	02/09/99
5,982,315	Bazarjani et al.	11/09/99
6,037,887	Wu et al.	03/14/00
6,057,793	Gong et al.	05/02/00
6,198,417	Paul	03/06/01
6,271,782	Steensgaard-Madsen	08/07/01

OTHER DOCUMENTS

Damien McCarthney et al., "A Low-Noise Low Drift Transducer ADC," IEEE J. solid State Circuits, 32(7):959-967 (Jul. 1997).

Donald A. Kerth et al., "An Oversampling Converter for Strain Gauge Transducers," IEEE J. solid State Circuits, 27(12): 1689-96 (Dec. 1992).

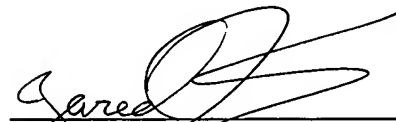
"16-bit/20-Bit Multi-Range ADC x/4-Bit Latch" Crystal Semiconductor Corporation 1996.

Copies of the aforementioned references, which are listed on the accompanying Form PTO-1449 (submitted in duplicate), are enclosed herewith.

It is respectfully requested that these documents be (1) fully considered by the Patent and Trademark Office during examination of this application; and (2) printed on any patent which may issue on this application. Applicant requests that a copy of Form PTO-1449, as considered and initialed by the Examiner, be returned with the next communication.

Consideration of the foregoing in relation to this
patent application is respectfully requested.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "Jared Kneitel", is written over a horizontal line.

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FORM PTO-449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE STATEMENT
BY APPLICANTDOCKET NO.
LT-171APPLICANT
Florin OprescuFILING DATE
February 12, 2004APPLN. NO.
10/779,292CONFIRMATION NO.
7415GROUP ART UNIT
2819

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	4,684,925	08/04/97	Maruta	341	143	
	4,704,600	11/03/87	Uchimura et al.	340	347	
	4,876,542	10/24/89	Van Bavel et al.	341	143	
	4,876,544	10/24/89	Kuraishi	341	166	
	5,010,347	04/23/91	Yukawa	341	143	
	5,148,167	09/15/92	Ribner	341	143	
	5,396,245	03/07/95	Rempfer	341	145	
	5,450,083	09/12/95	Brewer	341	143	
	5,675,334	10/07/97	McCartney	341	118	
	5,870,048	02/09/99	Kuo et al.	341	143	
	5,982,315	11/09/99	Bazarjani et al.	341	143	
	6,037,887	03/14/00	Wu et al.	341	143	
	6,057,793	5/02/00	Gong et al.	341	143	
	6,198,417	03/06/01	Paul	341	143	
	6,271,782	08/07/01	Steensgaard-Madsen	341	143	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL	
	Damien McCartney et al., "A Low-Noise Low Drift Transducer ADC," IEEE J. solid State Circuits, 32(7):959-967 (Jul. 1997).

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	DOCKET NO. LT-171	APPLN. NO. 10/779,292
	APPLICANT Florin Oprescu	CONFIRMATION NO. 7415
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